

15th IEEE European Test Symposium

Dorint Hotel Don Giovanni
Prague, Czech Republic
May 25–28, 2010
<http://www.ieee-ets.org>



The IEEE European Test Symposium (ETS) is Europe's premier forum dedicated to presenting and discussing scientific results, emerging ideas, practical applications, hot topics, and new trends in the area of electronic-based circuit and system testing. In 2010, ETS will take place in the nice city of Prague, Czech Republic. ETS'10 is being organized by the Czech Technical University in Prague together with Technical University in Liberec, and is sponsored by the Test Technology Technical Council (TTTC) of the IEEE Computer Society.

ETS'10 is offering commercial vendors the opportunity to give technical presentations in a track parallel to the technical paper sessions. These presentations will be listed in the symposium program along with the technical sessions, and should be targeted to the ETS technical audience. The Vendor Sessions differ from other ETS presentations in that company names, logos, and product names may be mentioned explicitly. Typical content could include product descriptions, case studies, best practices, and testimonials.

Presentation opportunities of 30-minute duration are available on a first-come first-served basis, but priority will be given to those companies that are also sponsors of ETS'09 – see below. Attendance at the sessions is open to all symposium attendees, and vendor representatives will be able to hand out literature at the session.

Selection Procedure

Proposals for the Vendor Sessions should be technical or application focused rather than overtly sales-and-marketing focused. Proposal selection is based on the technical content and relevance to ETS'10 audience and topics. The areas of interest of ETS'10 include (but are not limited to) the following topics:

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| • Automatic Test Generation | • Test(ability) Synthesis | • Failure Analysis |
| • Fault Modeling and Simulation | • Built-In Self Test (BIST) | • Diagnosis and Debug |
| • Current-Based Test | • Design for Test(ability) (DfT) | • Design Verification and Validation |
| • Power Issues in Test | • Test Data Compression | • Test Quality and Reliability |
| • Thermal Test | • On-Line Test | • Yield Analysis and Enhancement |
| • Delay and Performance Test | • Self-Repair Methodologies | • Defect and Fault Tolerance |
| • High-Speed IO/Interconnect Test | • Test of Reconfigurable Systems | • Board and System Test |
| • Signal Integrity Test | • Analog, Mixed-Signal, RF Test | • (Embedded) System Test |
| • Nanometer Technologies Test | • Memory Test and Repair | • High-Level DfT and TPG |
| • ATE Hardware and Software | • Microprocessor Test | • System-in-Package (SiP) Test |
| • Standards in Testing | • MEMS and Nanotechnology Test | • System-on-Chip (SoC) Test |

Submissions

A submission to the ETS'10 Vendor Sessions can be an abstract, extended abstract or full paper (max. six pages). Submission of a full paper is preferred, but not required. Proposals should be submitted via the ETS'10 web site; detailed submission instructions can also be found there (go to <http://www.ieee-ets.org>, follow the link to ETS'10, and then select Submission Instructions). Key dates for submissions:

- Submission deadline : **February 24, 2010**
- Notification of acceptance : **March 10, 2010**
- Camera-ready manuscript : **March 15, 2010**

ETS'09 Industrial Sponsorship

Every year, ETS is sponsored by several companies. The sponsorship money is used to reduce the registration fees and hence make the event more accessible to all its attendees. In return, the sponsoring companies are allowed to make publicity in various ways. ETS has defined four different sponsor grades (Bronze, Silver, Gold, and Platinum), each with different sponsorship amounts and publicity options. To find out more, contact Hans Manhaeve, details below.

More Information

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Visit the ETS web page at: <http://www.ieee-ets.org>

